



I WORKSHOP KOWLEDGE EXTRACTION BASED ON EVOLUTIONARY ALGORITHMS

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Some studies on the construction of artificial data sets for some data complexity measures

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1.- Introduction:

The aim of the study consists on the analysis of some complexity measures by means of the generation of artificial data sets.

To address this, we normalize the measures in a $[0,1]$ range, generating artificial data sets covering that range and studying graphically the instances distribution and some classifier behaviour.

2.- Overlap Complexity Measures

- Bayes error-based parametric and nonparametric approaches, entropy measures, nonparametric estimation including k nearest neighbor, Parzen estimation, etc.
- Scatter matrices.
- Information-theory-based approaches.
- Nonparametric methods.
- **Overlap between individual attribute values: Fisher's discriminant, volume of overlap region, feature efficiency, etc..**
- Measures of separability of classes: Linear Separability, Mixture identificability, etc.
- Measures of Geometry, Topology and Density of manifolds.
- ...

T.K. Ho, M. Basu (2002). Complexity Measures of Supervised Classification Problems, IEEE Trans. on Pattern Analysis and Mach. Intell. 24:3, 289-300.

S. Singh (2003). Multiresolution Estimates of Classification Complexity, IEEE Transactions on Pattern Analysis and Machine Intelligence 25:12, 1534-1539.

E. Bernadó-Mansilla, T.K. Ho, A. Orriols-Puig (2006). Data Complexity and Evolutionary Learning: Classifier's Behavior and Domain of Competence. In: T.K. Ho, M. Basu (Eds.) Data Complexity in Pattern Recognition, Springer, accepted

2.1. Fisher's Discriminant Ratio

Measure: **Fisher's Discriminant Ratio (F1)**

Behaviour: Small values indicate High overlap

Cites: [Bernadó et al. 2005] , [Dong et al. 2003] , [Hernandez et al. 2005], [Ho et al. 2000], [Ho et al. 2002a], [Ho et al. 2002b], [Ho et al. 2006], [Mollineda et al 2005], [Sotoca et al. 2006]

Definition: For each feature, the measure f is calculated as:

$$f = \frac{(\mu_1 - \mu_2)^2}{\sigma_1^2 + \sigma_2^2}$$

where $\mu_1, \mu_2, \sigma_1^2, \sigma_2^2$ are the means and variances of the two classes respectively.

It is used the maximum over all the feature dimensions to describe a problem.

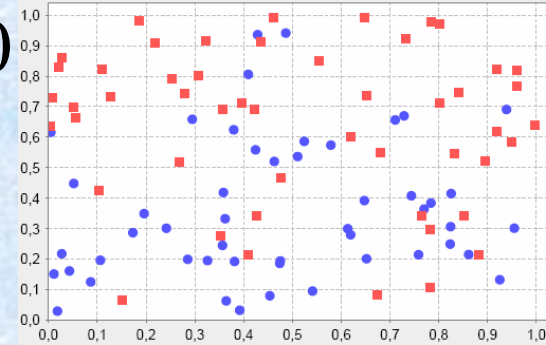
2.1. Fisher's Discriminant Ratio

Measure: **Fisher's Discriminant Ratio (F1)**

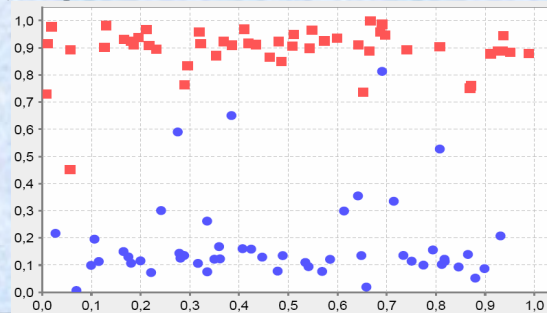
Artificial datasets:

Instances=100, Features=2,
Classes=2

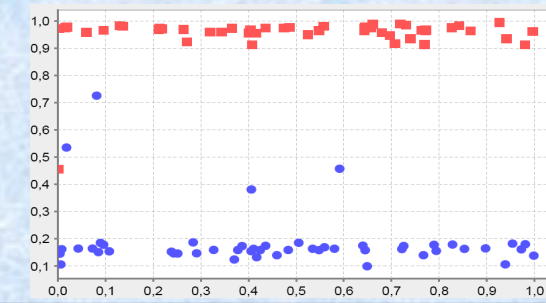
F1=0



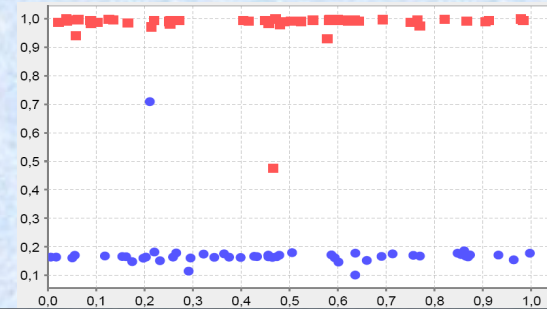
F1=0.25



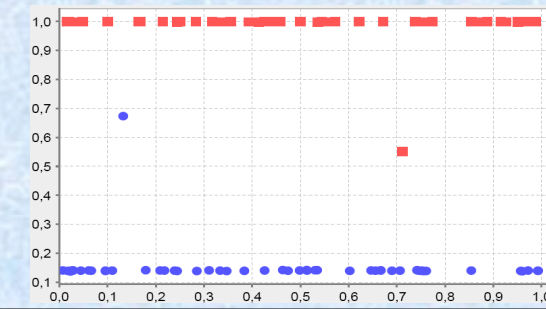
F1=0.5



F1=0.75



F1≈1.0

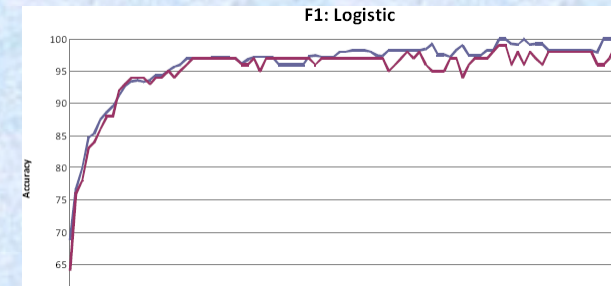
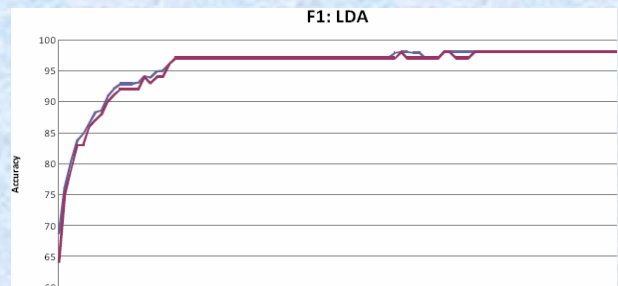
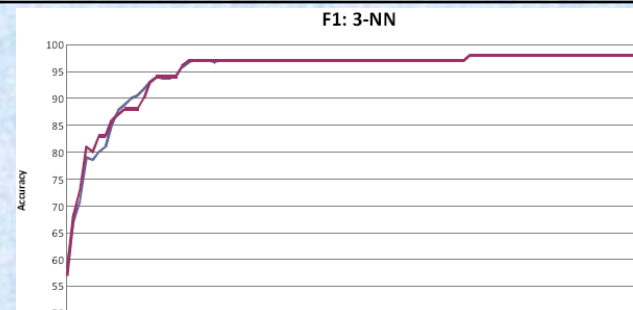
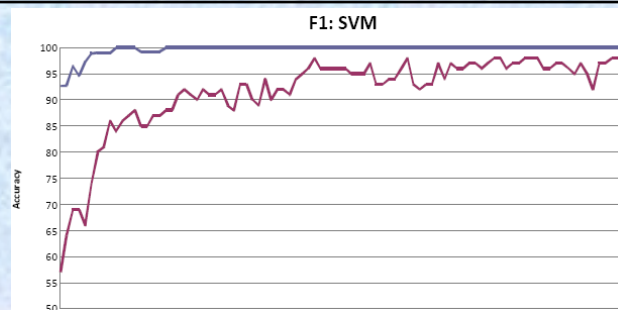
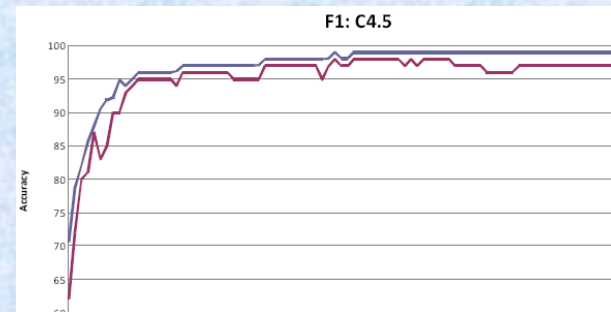


2.1. Fisher's Discriminant Ratio

Measure: **Fisher's Discriminant Ratio (F1)**

*Classifier Behaviour with
Artificial Datasets:*

Instances=100, Features=4,
Classes=2



2.1. Fisher's Discriminant Ratio

Measure: Fisher's Discriminant Ratio (F1)

Generalization (Multiclass extension):

Considering [Ho et al. 2006]:

$$f = \frac{\sum_{i=1, j=1, i \neq j}^C p_i p_j (\mu_i - \mu_j)^2}{\sum_{i=1}^C p_i \sigma_i^2}$$

- Considering [Mollineda et al 2005], [Sotoca et al 2006]:

They propose a measure of the separability among the classes based in nearest neighbor distance.

$$F1 = \frac{\sum_{i=1}^C n_i \cdot \delta(m, m_i)}{\sum_{i=1}^C \sum_{j=1}^{n_i} \delta(x_j^i, m_i)}$$

where n_i denotes the number of samples in class i , δ is a metric, m is the overall mean, m_i is the mean of class i , and x_j^i represents the sample j belonging to class i .

2.2. Volume of Overlap Region

Measure: **Volume of Overlap Region (F2)**

Behaviour: Small value indicate Small overlap

Cites: [Bernadó et al. 2005] , [Dong et al. 2003] , [Hernandez et al. 2005], [Ho et al. 2000], [Ho et al. 2002a], [Ho et al. 2002b], [Ho et al. 2006], [Mollineda et al 2005], [Sotoca et al 2006]

Definition:

$$F2 = \prod_i \frac{MIN(max(f_i, c_1), max(f_i, c_2)) - MAX(min(f_i, c_1), min(f_i, c_2))}{MAX(max(f_i, c_1), max(f_i, c_2)) - MIN(min(f_i, c_1), min(f_i, c_2))}$$

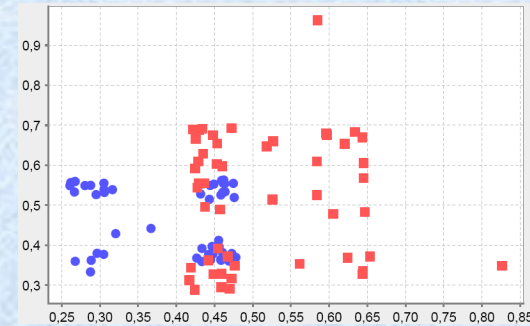
2.2. Volume of Overlap Region

Measure: Volume of Overlap Region (F2)

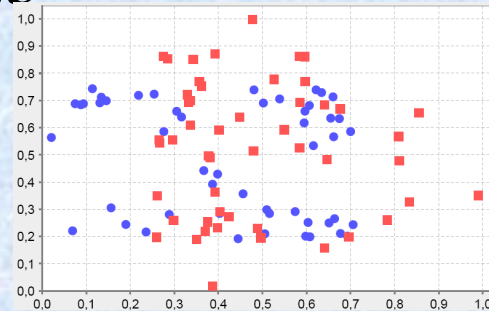
Artificial datasets:

Instances=100, Features=2,
Classes=2

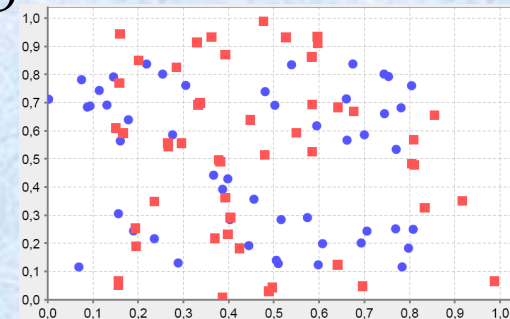
$F2 \approx 0$



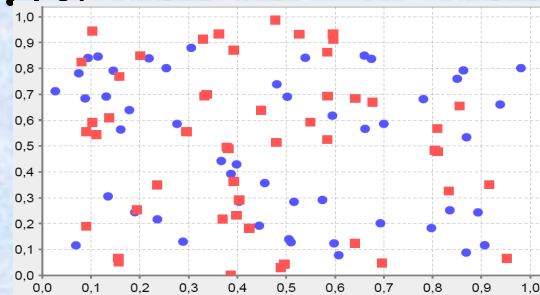
$F2 = 0.25$



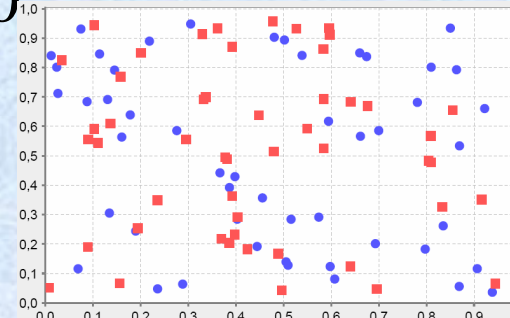
$F2 = 0.5$



$F2 = 0.75$



$F2 = 1.0$

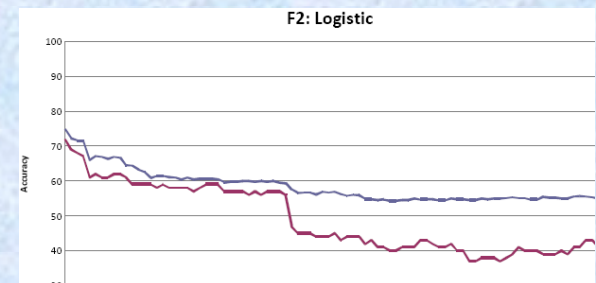
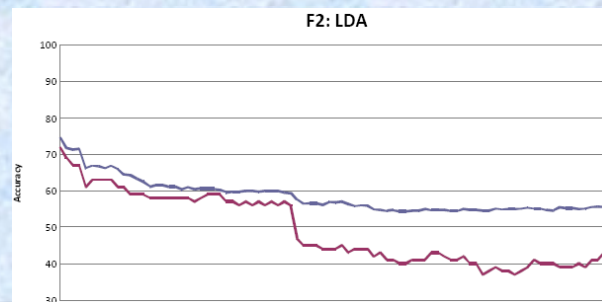
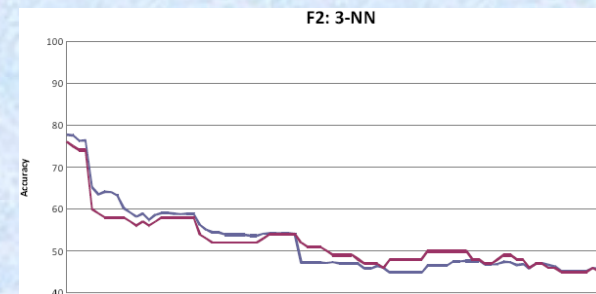
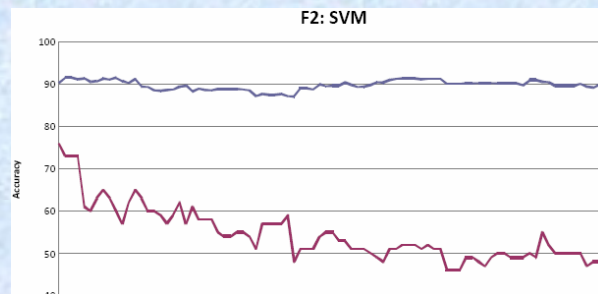
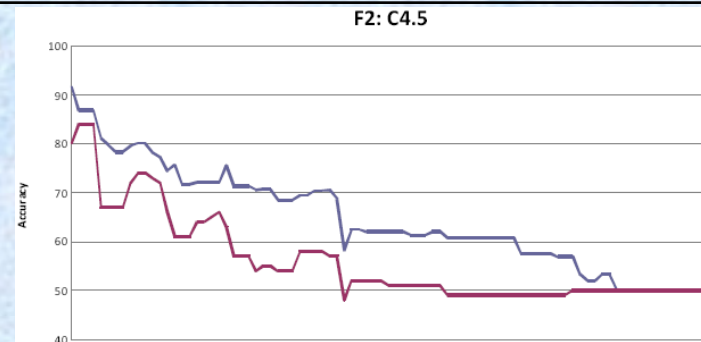


2.2. Volume of Overlap Region

Measure: Volume of Overlap Region (F2)

*Classifier Behaviour with
Artificial Datasets:*

Instances=100, Features=4,
Classes=2



2.2. Volume of Overlap Region

Measure: Volume of Overlap Region (F2)

Generalization (Multiclass extension):

- Considering [Ho et al. 2006], [Mollineda et al 2005], [Sotoca et al 2006]:

$$f = volume \quad of \quad \sum_{i,j,i \neq j} V_i \cap V_j$$

Being V_i the hyperrectangular region spanned by the i th class.

2.3. Feature Efficiency

Measure: **Feature Efficiency (F3)**

Behaviour: Small values indicate High overlap

Cites: [Bernadó et al. 2005] , [Dong et al. 2003] , [Hernandez et al. 2005], [Ho et al. 2000], [Ho et al. 2002a], [Ho et al. 2002b], [Ho et al. 2006], [Mollineda et al 2005], [Sotoca et al 2006]

Definition:

The efficiency of each feature is the fraction of all remaining points separable by that feature. It is used the maximum feature efficiency to represent the contribution of the feature most usefull.

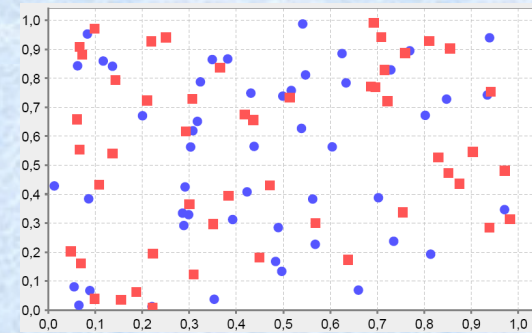
2.3. Feature Efficiency

Measure: Feature Efficiency (F3)

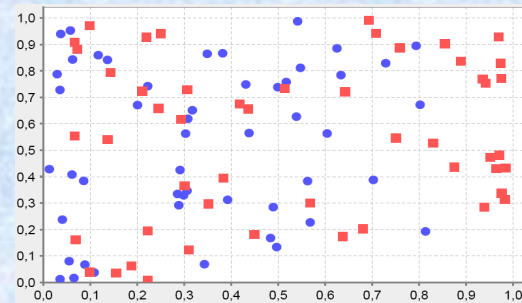
Artificial datasets:

Instances=100, Features=2,
Classes=2

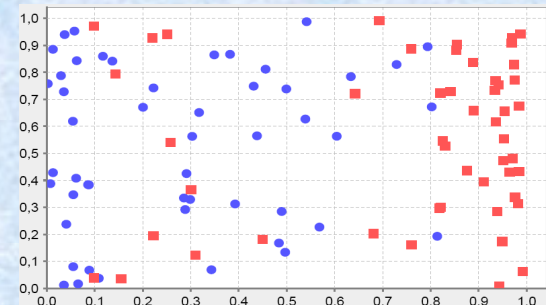
F2=0



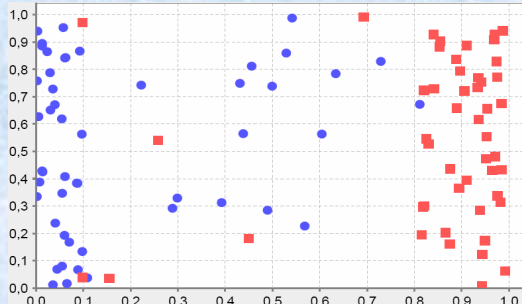
F2=0.25



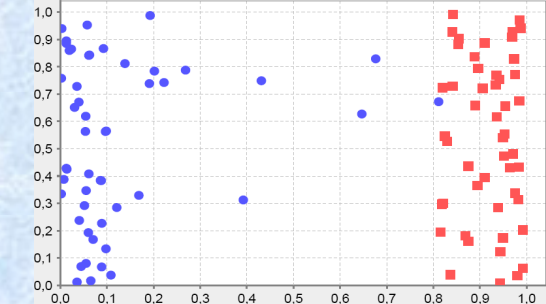
F2=0.5



F2=0.75



F2=1.0

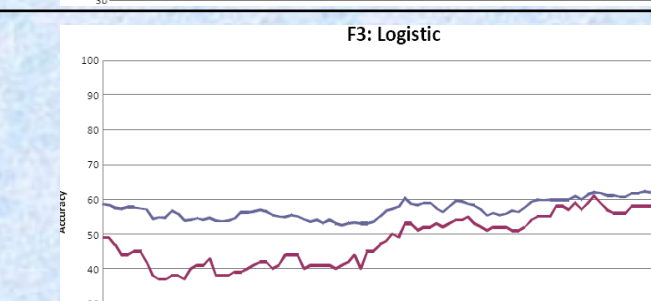
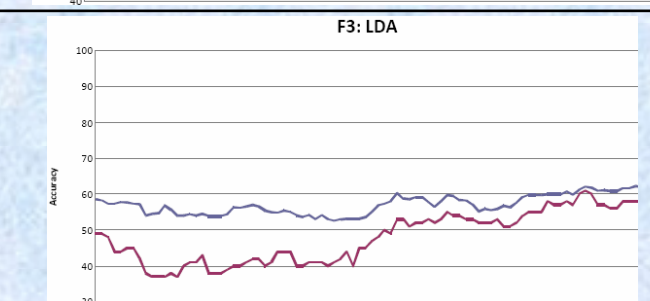
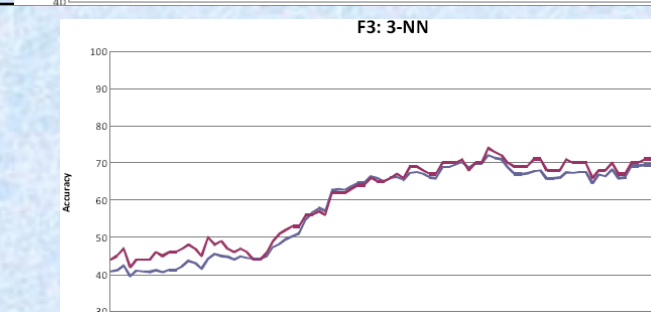
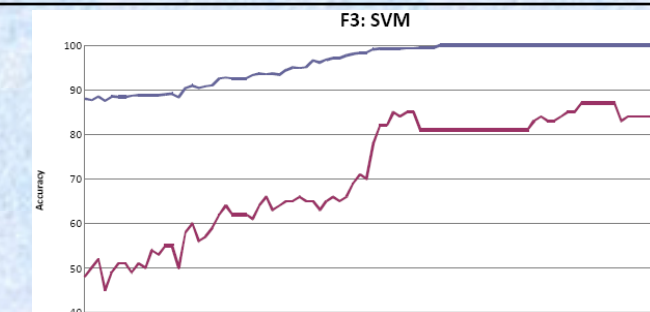
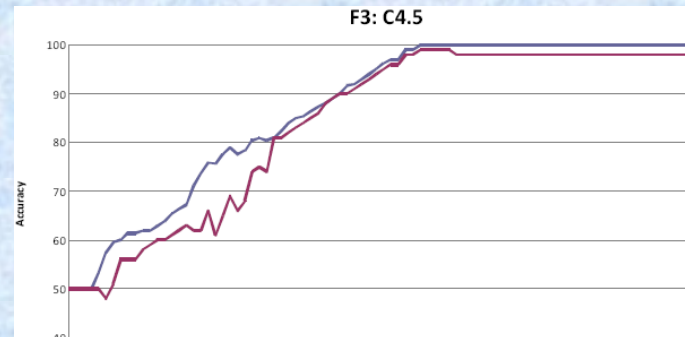


2.3. Feature Efficiency

Measure: Feature Efficiency (F3)

*Classifier Behaviour with
Artificial Datasets:*

Instances=100, Features=4,
Classes=2



2.3. Feature Efficiency

Measure: Feature Efficiency (F3)

Generalization (Multiclass extension):

- Considering [Ho et al. 2006], [Mollineda et al 2005], [Sotoca et al 2006]:

“The measure value for C classes is the overall fraction of points in some overlap range of any feature for any pair of classes. Points in more than one range is counted once.”

3.- Conclusions

- **The graphical instance distribution helps to understand the effect of the measures variation in instances distribution.**
- **SVM seems to be very sensible to overlapping.**
- **C4.5, when F3 is higher, is the classifier which offers the most interesting behaviour.**
- **It would be needed a more complex environment (with higher number of instances, features and classes) for the artificial data sets to analyze the rest of the classifiers.**

4.- Future Works.

- **Increase the environment (complexity) of the artificial data sets.**
- **Increase the number of measures considered.**
- **Extend the measures and their analysis to multiclass context.**

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